



Integrated Device Technology, Inc.  
6024 Silver Creek Valley Road, San Jose, CA 95138

## PRODUCT/PROCESS CHANGE NOTICE (PCN)

<b>PCN #:</b> F1206-02 <b>Product Affected:</b> 80HCPS1848CZ, 80HVPS1848CZ, 80HCPS1432CZ, 80HVPS1616CZ (Refer to Attachment I) <b>Date Effective:</b> September 25, 2012	<b>DATE:</b> June 25, 2012	<b>MEANS OF DISTINGUISHING CHANGED DEVICES:</b> <input checked="" type="checkbox"/> Product Mark      Change in Ordering Part Number <input type="checkbox"/> Back Mark <input type="checkbox"/> Date Code <input type="checkbox"/> Other
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<b>Contact:</b> Mary Vesey <b>Title:</b> Director, Product Assurance <b>Phone #:</b> (408) 284-4565 <b>Fax #:</b> (408) 284-1450 <b>E-mail:</b> <a href="mailto:mary.vesey@idt.com">mary.vesey@idt.com</a>	<b>Attachment:</b> <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No  <b>Samples:</b> Samples are available now.
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**DESCRIPTION AND PURPOSE OF CHANGE:**

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input checked="" type="checkbox"/> Other - Die Revision Change	<p>This notification is to advise our customers that IDT has qualified a new die revision C to correct the functional errata. There will be a change in ordering part number and device top mark.</p> <p>There is no change in die technology/process.</p> <p>Please see attachment for details.</p>
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**RELIABILITY/QUALIFICATION SUMMARY:**

See attached data. There is no change in die technology/process.

**CUSTOMER ACKNOWLEDGMENT OF RECEIPT:**

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone # /Fax #: _____

**CUSTOMER COMMENTS:** \_\_\_\_\_

**IDT ACKNOWLEDGMENT OF RECEIPT:**

RECD. BY: \_\_\_\_\_ DATE: \_\_\_\_\_



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### ATTACHMENT I - PCN #: F1206-02

**PCN Type:** Die Revision Change

**Data Sheet Change:** Yes

**Detail of Change:**

This notification is to advise our customers that IDT has qualified a new die revision C to correct the functional errata. There will be a change in ordering part number and device top mark as shown in Table 1.

**Table 1**

Old Ordering Part Number	New Ordering Part Number	Old Ordering Part Number	New Ordering Part Number
80HCPS1432RM	80HCPS1432CRM	80HCPS1848RM-5	80HCPS1848CRM-5
80HCPS1432RMI	80HCPS1432CRMI	80HCPS1848RMI	80HCPS1848CRMI
80HCPS1848BR	80HCPS1848CBR	80HCPS1848RMI-5	80HCPS1848CRMI-5
80HCPS1848BRI	80HCPS1848CBRI	80HVPS1616BR	80HVPS1616CBR
80HCPS1848HM	80HCPS1848CHM	80HVPS1616BRI	80HVPS1616CBRI
80HCPS1848HMI	80HCPS1848CHMI	80HVPS1848RM	80HVPS1848CRM
80HCPS1848RM	80HCPS1848CRM	80HVPS1848RMI	80HVPS1848CRMI

**Qualification Test Plan and Result:**

Qualification Plan #: QSM-1004-01R1

Qual Vehicle: 80HCPS1848C

Test Description	Test Method (Latest specs in effect)	Test Results (SS / Rej)
Operating Lifetest (Dynamic) 125°C@1000 Hrs	JESD22-A108B	77/0, 77/0, 77/0
Temperature Humidity Bias 85°C/85%RH@1000 Hrs	JESD22-A101	25/0, 25/0, 25/0
Unbiased Highly Accelerated Stress Test 130°C/85%RH@100 Hrs	JESD22-A118	25/0, 25/0, 25/0
Temperature Cycle -55°C to 125°C@700 Cycles	JESD22-A104B	25/0, 25/0, 25/0
High Temperature Storage Bake 150°C@1000 Hrs	JESD22-A103B	25/0, 25/0, 25/0
ESD: Human Body Model @ 2000V	JESD22-A114F	3/0
ESD: Charged Device Model @ 500V	JESD22-101C	3/0
Latch-up	JESD78	6/0

Note: For UHAST, THB and Temperature Cycle, samples have been subjected to pre-conditioning per JESD22-A113D Level 4 flow.



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### ATTACHMENT I - PCN #: F1206-02

**Qual Vehicle:** 80HCPS1432C

Test Description	Test Method (Latest specs in effect)	Test Results (SS / Rej)
Operating Lifetest (Dynamic) 125°C@1000 Hrs	JESD22-A108B	77/0, 77/0, 77/0
Temperature Humidity Bias 85°C/85%RH@1000 Hrs	JESD22-A101	25/0, 25/0, 25/0
Unbiased Highly Accelerated Stress Test 130°C/85%RH@100 Hrs	JESD22-A118	25/0, 25/0, 25/0
Temperature Cycle -55°C to 125°C@700 Cycles	JESD22-A104B	25/0, 25/0, 25/0
High Temperature Storage Bake 150°C@1000 Hrs	JESD22-A103B	25/0, 25/0, 25/0
ESD: Human Body Model @ 2000V	JESD22-A114F	3/0
ESD: Charged Device Model @ 500V	JESD22-101C	3/0
Latch-up	JESD78	6/0

Note: For UHAST, THB and Temperature Cycle, samples have been subjected to pre-conditioning per JESD22-A113D Level 4 flow.

**Qual Vehicle:** 80HVPS1616C

Test Description	Test Method (Latest specs in effect)	Test Results (SS / Rej)
Operating Lifetest (Dynamic) 125°C@1000 Hrs	JESD22-A108B	77/0, 77/0, 77/0
Temperature Humidity Bias 85°C/85%RH@1000 Hrs	JESD22-A101	25/0, 25/0, 25/0
Unbiased Highly Accelerated Stress Test 130°C/85%RH@100 Hrs	JESD22-A118	25/0, 25/0, 25/0
Temperature Cycle -55°C to 125°C@700 Cycles	JESD22-A104B	25/0, 25/0, 25/0
High Temperature Storage Bake 150°C@1000 Hrs	JESD22-A103B	25/0, 25/0, 25/0
ESD: Human Body Model @ 2000V	JESD22-A114F	3/0
ESD: Charged Device Model @ 500V	JESD22-101C	3/0
Latch-up	JESD78	6/0

Note: For UHAST, THB and Temperature Cycle, samples have been subjected to pre-conditioning per JESD22-A113D Level 4 flow.